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ATTY. DOCKET NO.

500.34397CV2

SERIAL NO.

divisional of
08/610,488

APPLICANT

MIURA, et al.

FILING DATE

October 16, 2001

GROUP (of parent)

2813

10/16/01
09/977207
JC971 U.S. PTO



U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
T.D	5 2 9 0 7 1 8	3-94	Fearon, et al.	—	—	
	5 0 4 5 4 9 2	9-91	Huie, et al.	—	—	
	5 6 3 7 5 2 8	6/97	Higashitani et al	—	—	
	5 2 1 0 0 5 6	5/93	Pong et al	—	—	
	5 1 5 1 3 8 1	9/92	Liu et al	—	—	
	5 1 3 2 2 4 4	7/92	Roy	—	—	
T.D	3 8 5 3 6 3 3	12/74	Armstrong	—	—	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
T.D	0 2 1 4 4 2 1	3-87	Europe	—	—	
	5 7 2 0 7 3 6 6	12-82	Japan	—	—	abstract
	5 8 0 3 9 0 1 4	3-83	Japan	—	—	abstract
	6 2 0 9 4 9 2 6	5-87	Japan	—	—	
	0 3 2 5 7 8 2 8	1991	Japan	—	—	abstract
	0 5 2 6 7 3 3 3	1993	Japan	—	—	abstract
	0 4 3 1 6 3 3 2	1992	Japan	—	—	abstract
T.D	A 3 1 1 7 3 3	1989	Japan	—	—	abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

T.D	Patent Abstract of Japan - Publication No. 01255228 - Publication Date October 1989
T.D	Patrice Deroux-Dauhphin er al.: "Physical and electrical characterization of a SILO Isolation structure", IEEE Transactions On Electron Devices, vol. ED-32, no. 11, November 1985, pages 2392-2398

EXAMINER

T. DAVE

DATE CONSIDERED

2/25/02

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.